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Anomaly Detection and Imaging with X-Rays (ADIX) III

Amit Ashok
Joel A. Greenberg
Michael E. Gehm
Mark A. Neifeld
Editors

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Contents

v *Authors*
vii *Conference Committee*

DEEP LEARNING TECHNIQUES IN X-RAY SCREENING

10632 03 **Automatic threat recognition of prohibited items at aviation checkpoint with x-ray imaging: a deep learning approach (Invited Paper)** [10632-2]

10632 04 **Deep learning based sparse view x-ray CT reconstruction for checked baggage screening** [10632-3]

10632 05 **Application of machine learning to x-ray diffraction-based classification** [10632-4]

SCATTER-BASED IMAGING AND DETECTION I

10632 09 **Towards an x-ray-based coded aperture diffraction system for bulk material identification (Invited Paper)** [10632-8]

SCATTER-BASED IMAGING AND DETECTION II

10632 0B **The role of texturing in x-ray diffraction tomography** [10632-10]

SYSTEMS ANALYSIS AND ALGORITHMS

10632 0D **Joint reconstruction and material classification in spectral CT (Invited Paper)** [10632-12]

10632 0E **Consensus relaxation on materials of interest for adaptive ATR in CT images of baggage (Invited Paper)** [10632-13]

10632 0F **An information theoretic approach to system optimization accounting for material variability** [10632-14]

Authors

Numbers in the index correspond to the last two digits of the seven-digit citation identifier (CID) article numbering system used in Proceedings of SPIE. The first five digits reflect the volume number. Base 36 numbering is employed for the last two digits and indicates the order of articles within the volume. Numbers start with 00, 01, 02, 03, 04, 05, 06, 07, 08, 09, 0A, 0B...0Z, followed by 10-1Z, 20-2Z, etc.

Ashok, Amit, 04, 0F
Babaheidarian, Parisa, 0D
Bilgin, Ali, 04
Carin, Lawrence, 03
Carlson, David, 03
Castañón, David A., 0D
Chandrasekaran, Hema, 0E
Coccarelli, David, 0F
Diallo, Souleymane O., 03, 09
Gehm, Michael, 0F
Greenberg, Joel A., 05, 09, 0B, 0F
Gregory, Christopher, 03, 09
Hazineh, Dean, 0B
Heilmann, Geert, 03
Keohane, Brian, 0B
Liang, Kevin J., 03
MacGibbon, Chris, 0B
Mandava, Sagar, 04
Martz, Harry E., 0E
Masoudi, Ahmad, 0F
Paglieroni, David W., 0E
Pechard, Christian, 0E
Roe, Kris, 03, 09
Sigman, John B., 03
Spell, Gregory P., 03
Tadlock, K., 09
Thamvichai, Ratchaneekorn, 0F
Voris, Jay, 0F
Wolter, Scott, 05, 09, 0B
Zhao, Bi, 05

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